

Notice of References Cited	Application/Control No. 10/565,930		Applicant(s)/Patent Under Reexamination VAN DER TOL, ERIK BOUDEW	
	Examiner Blane J. Jackson		Art Unit 2618	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,949,484	09-1999	Nakaya et al.	348/384.1
*	B	US-2004/0158878	08-2004	Ratnakar et al.	725/150
*	C	US-6,229,570	05-2001	Bugwadia et al.	348/441
*	D	US-2002/0118296	08-2002	Schwab et al.	348/441
*	E	US-2004/0252230	12-2004	Winder, Simon Anthony John	348/402.1
*	F	US-7,246,249	07-2007	Shiiyama, Hirotaka	713/320
*	G	US-2003/0123844	07-2003	Toma et al.	386/46
*	H	US-7,062,250	06-2006	Kosaka, Akio	455/343.5
*	I	US-7,076,234	07-2006	Grivas et al.	455/343.1
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	I					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.